FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE OPE CONFORMATION DISCLOSURE STATEMENT BY APPLICANT BY APPLICANT (Use several sheets if necessary) FILING DATE January 10, 2002 GROUP 2122

RAU			U.S. PAT	ENT DOCUMENTS				
EXAMINER'S		PATENT	ISSUE				FILING	F
INITIALS		NUMBER	DATE	NAME	CLASS	SUBCLASS	APPRO	PRIATE
						REC Aug Technology		
						AFI	1 2	
							EH	
						AUG	7	40 -
						Technol	9 200	,
							b	
						/	enter 2	100
							//	(6
					*	<u>5</u> 15		
			FOREIGN F	PATENT DOCUMENTS				-
	[DOCUMENT	PUBLICATION				TRANSLATION	
		NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO*
		OTHER DO	CUMENTS (Includi	ng Author, Title, Date, Pe	ertinent Pages	, Etc.)		
anz	AA	"An Enterprise Wide Calibration and Results Information Management System," Proceedings of National Conference of Standards Laboratories, Vol. 2, pp. 627-634 (August 25-29, 1996)						
anz anz	AB	Puls, Carsten, "PXI and VXI Modular Instrumentation in the New Millennium," National Instruments, Austin, TX, pp. 623-625						
arz	AC	"Nose Out Application Troubles with CYRANO Impact," Infoworld Review CYRANO Impact, pp. 1-3 (2001)						

2700 IDS 1449 form

Andre D. Foulle 11/1/04